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PURSUANT TO 37 C.F.R. ' 1.10, I HEREBY CERTIFY THAT I HAVE A REASONABLE BASIS FOR BELIEF THAT THIS CORRESPONDENCE IS BEING DEPOSITED WITH THE UNITED STATES POSTAL SERVICE AS EXPRESS MAIL POST OFFICE TO ADDRESSEE ON THE DATE INDICATED BELOW, AND IS ADDRESSED TO:

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Gordon Ma et al. Group Art Unit: Serial No.: Examiner: Filing Date: February 27, 2004

Title: Semiconductor Structure Attny. Docket No. 068736.0236 Client Ref.: 2003P54948US

INFORMATION DISCLOSURE STATEMENT

Sir:

Applicants respectfully request, pursuant to 37 C.F.R. §§1.56, 1.97 and 1.98, that the art listed on the attached PTO-1449 form be considered and cited in the examination of the above-identified application. A copy of the cited art is enclosed for the convenience of the Examiner.

Furthermore, pursuant to 37 C.F.R. §§1.97(g) and (h), no representation is made that these references are material to the patentability of the present application.

As the Information Disclosure Statement is being submitted before the mailing of

the first office action on the merits, Applicants believe that no fee is required. If a fee is required, please accept this transmittal as a petition therefor and charge any fee to Baker Botts L.L.P. (formerly, Baker & Botts, L.L.P.) Deposit Account No. 02-0383, Order No. (068736.0236) for any other charges necessary for the filing of this Information Disclosure Statement.

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PATENT Client Reference No. 068736.0236 Application No. Applicant(s): PTO-1449 GORDON MA ET AL. **Information Disclosure Citation** Group Art Unit Filing Date Docket Number in an Application February 27, 2004 068736.0236 **U.S. PATENT DOCUMENTS** DOCUMENT NO. DATE NAME **CLASS SUBCLASS** FILING DATE 1 03/07/89 357 46 04/24/87 4,811,075 Eklund 2 357 23.4 03/18/91 5,155,563 10/13/92 Davies et al. 3 02/03/92 5,252,848 10/12/93 Adler et al. 257 328 4 262 02/16/93 05/17/94 Eklund 257 5,313,082 5 01/02/01 02/05/99 Rumennik et al. 438 188 6,168,983 6 05/13/03 257 342 11/12/02 6,563,171 Disney FOREIGN PATENT DOCUMENTS TRANSLATION DOCUMENT NO. DATE COUNTRY **CLASS** SUBCLASS YES NO NON-PATENT DOCUMENTS DOCUMENT (Including Author, Title, Source, and Pertinent Pages) DATE J.A. Appels and H.M.J. Vaes, "High voltage thin layer devices (RESURF devices)", IEDM 7 1979 technical digest, pp. 238-241 H.M.J. Vaes and J.A. Appels, "High voltage high current lateral devices", IEDM technical 1980 8 digest, pp. 87-90 T. Fujihira, "Theory of Semiconductor Superjunction Devices", Jpn. J. Appl. Phys., vol. 36, pp. 9 1997 pp. 6254-6262 G. Deboy, et al., "A new generation of high voltage MOSFETs breaks the limit line of silicon", 1998 10 IEDM technical digest, pp. 683-685 11 A. Ludikhuize, "A review of RESURF technology", Proc. of ISPSD, p. 11 2000 J. Cai, et al., "A novel high performance stacked LDD RF LDMOSFET, IEEE Electron Device 12 2001 Lett., vol. 22, no. 5, pp. 236-238 J.G. Mena and C.A.T. Salama, "High voltage multiple-resistivity Drift-Region LDMOS", Solid 1986 13 State Electronics, Vol. 29, No. 6, pp. 647-656 M.D. Pocha and R.W. Dutton, "A computer-aided design model for High-Voltage Double 1976 14 Diffused MOS (DMOS) Transistors", IEEE Journal of Solid-State Circuits, Vol. SC-11, No. 5 I. Yoshia, et al.; "Highly Efficient 1.5 GHz Si Power MOSFET for Digital Cellular Front End"; Proceedings of International Symposium on Power Semiconductor Devices & ICs; Tokyo, pp. 1992 15 Helmut Brech et al; "Record Efficiency and Gain at 2.1 GHz of Hih Power RF Transistors for Cellular and 3G Base Stations"; RF & DSP INfrastructure Devision, Semiconductor Products 16 2003 Sector, Motorola, Tempe, Arizona

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

DATE CONSIDERED

EXAMINER